

# Introduction to Microelectronics Technologies and Industry

Satoshi Hamaguchi University of Osaka



# Outline

- 1. The semiconductor industry
  - overview
  - technology roadmap
  - brief history
- 2. Outline of chip products: logic, memory, storage,
- 3. Fundamentals of device physics
- 4. Fundamentals of Chip Manufacturing
  - Front-end processes (FEOL & BEOL)
  - Back-end processes
- 5. Summary

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# Semiconductor Industry: growth & challenges

- Continued growth: WW Revenues of \$628 (2024) up by 19.1% from \$527 B (2023)
- The supply chain is global, causing concern on national security issues.
- End of Moore's law; paradigm shift in technology
  - Sizes of some devices are approaching atomic scale
  - Devices with new materials & new 3D structures must be manufactured.
- For the manufacturing of advanced semiconductor products,
   plasma processing is becoming one of the bottle-neck technologies.

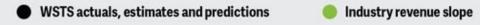
https://www.idc.com/getdoc.jsp?containerId=IDC P19632

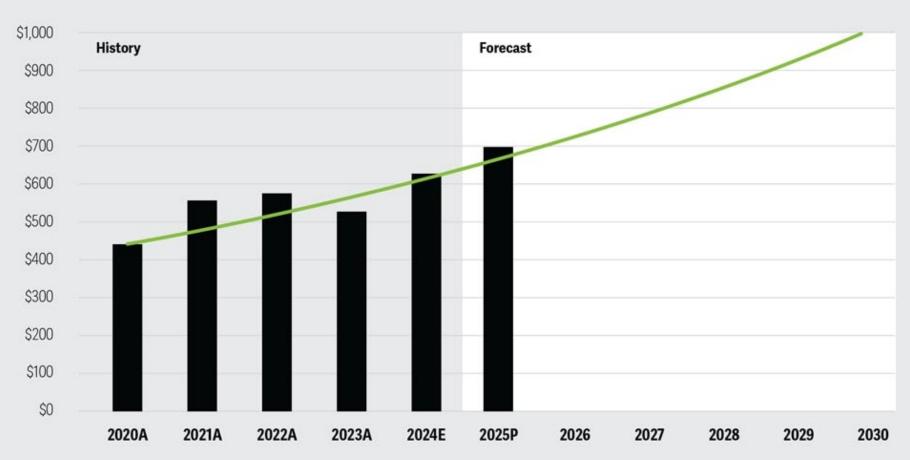
https://www.semiconductors.org/global-semiconductor-sales-increase-19-1-in-2024-double-digit-growth-projected-in-2025/

Figure 1

#### Revenues indicate the possibility of the chip industry hitting US\$1 trillion in 2030

The path to \$1 trillion in semiconductor revenues (\$Billions)

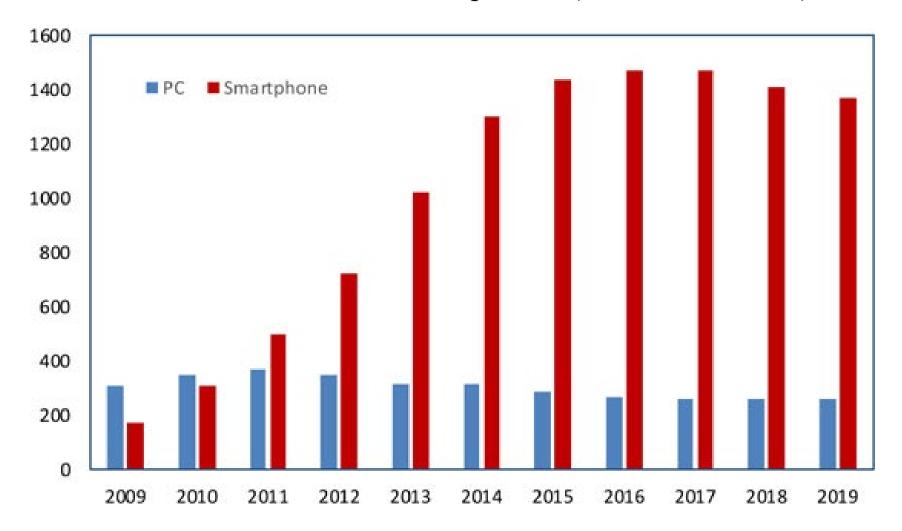




Note: A = Actual, E = Estimate, P = Prediction.

Source: Deloitte analysis and extrapolation based on data from World Semiconductor Trade Statistics.

#### Global Sales of PCs and Smartphones (Millions of Units)



Published in May 2020: IMF e-Library https://www.elibrary.imf.org/view/journals/001/2020/070/article-A001-en.xml

### Amount of data created and stored each year

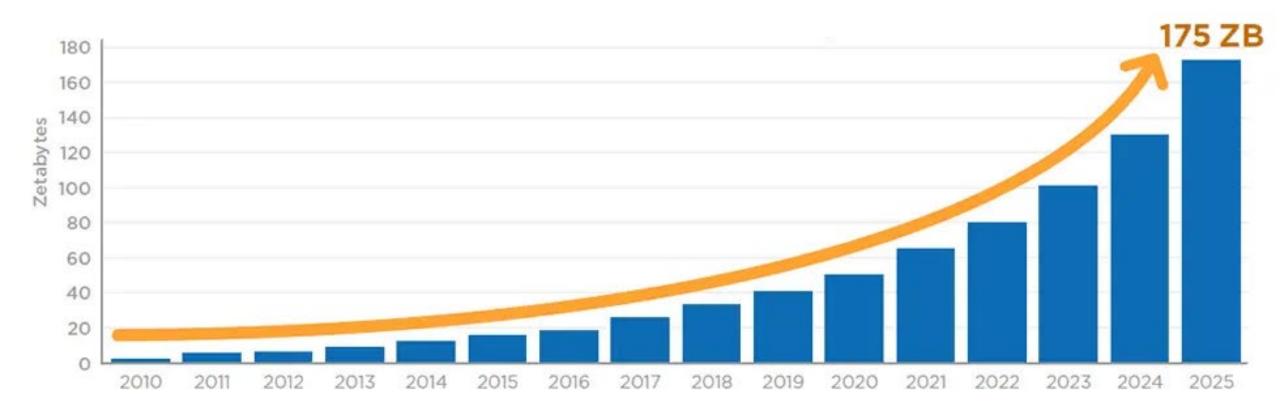
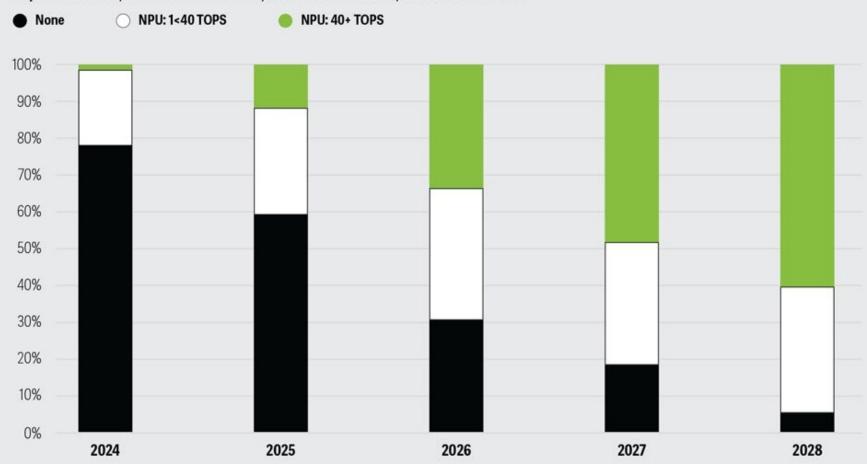


Figure 4

# Almost all PCs are expected to have some gen Al processing—also known as neural processing units (NPUs)—by 2028

Expected sales of NPU-enabled PCs of all PCs worldwide from 2024 to 2028



Note: TOPS = trillion operations per second.

Source: International Data Corporation Worldwide Quarterly Personal Computing Device Tracker, September 2024.

# AI will drive the future semiconductor industry

- AI data centers
- Edge computing<sup>1)</sup> (Pervasive computing)
- Autonomic computing<sup>2)</sup>

- 1) "What is the edge computing" https://www.ibm.com/topics/edge-computing
- 2) Autonomic computing (AC) is distributed computing resources with self-managing characteristics, adapting to unpredictable changes while hiding intrinsic complexity to operators and users (https://en.wikipedia.org/wiki/Autonomic\_computing)

#### **Typical Global Semiconductor Production Pattern Equipment IDM** or foundry **IDM or Fabless** Semiconductor Front-end fabrication Raw materials machinery is sold to Ingots are formed Semiconductors are producers for front-Design created on silicon wafers from pure silicon end and back-end Semiconductor and then sliced using various processes manufacturing. designs are created into wafers. and techniques (e.g., using highly sophistietching, photolithogracated computer and phy, materials depositing). software design tools. **IDM** or Foundry South Korea (Samsung, SK Hynix) **Equipment** Netherlands (ASML) Foundry Back-end assembly, Taiwan test, and packaging **Outsourced ATP** (TSMC) Semiconductors are cut out of the wafers. tested, encapsulated into plastic packages, and prepared for purchase. **Electronic product sales** Electronic product manufacturing

Finished semiconductors are sold,

typically to downstream electronic

product manufacturers, and incorporated into electronic products.

**IDM:** Integrated Device Manufacture ATP: Assembly, Test, and Packaging

For illustrative purposes only.

Congressional Research Service (CRS) Semiconductors: U.S. Industry, Global Competition, and Federal Policy (October 26, 2020, R46581, https://crsreports.congress.gov)

**Source:** CRS, adapted from information provided by SIA.

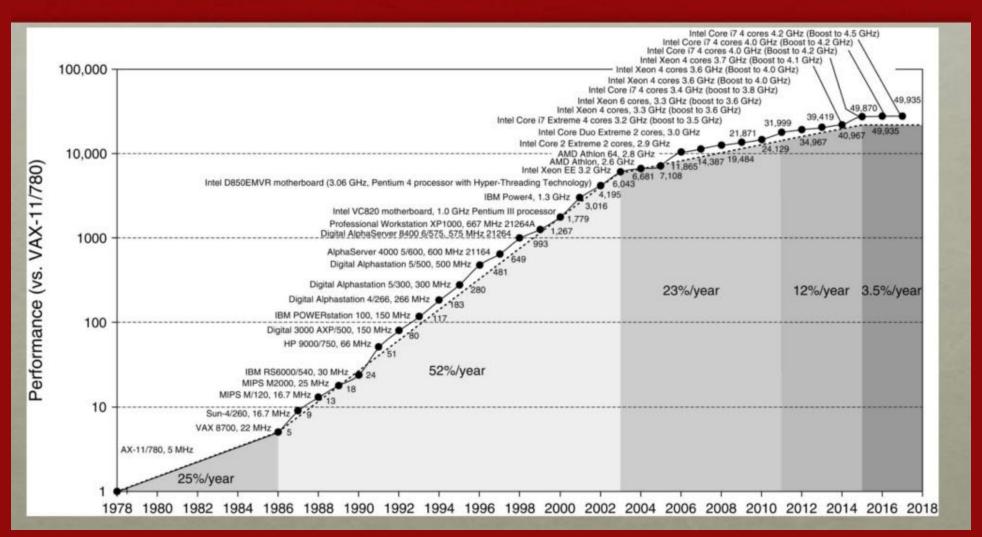
Final electronic products

are sold to consumers.

with semiconductors inside

#### **End of Moore's Law**

# Uniprocessor Performance (SINGLE CORE)



### ...yet critical applications are also undergoing a paradigm shift

Compute-centric paradigm

Main Focus:

Solve differential equations

**Bottleneck:** 

CPU / Memory

Typical Examples:

Computational Fluid Dynamics

Finite Element Analysis

**Multi-body Simulations** 



Extrapolation to 2020

(at 90% CGR  $\rightarrow$  need **1.7 PB/sec**)

- 5.6 million HDD
  - **19,000** sq. ft. !!
  - 25 Megawatts

**Data**-centric paradigm

**Analyze petabytes of data** 

Storage & I/O

Search and Mining

Analyses of social/terrorist networks

Sensor network processing

Digital media creation/transmission

Environmental & economic modeling

(at 90% CGR → need **8.4G SIO/sec**)

- 21 million HDD
  - **70,000** sq. ft. !!
  - 93 <u>Mega</u>watts

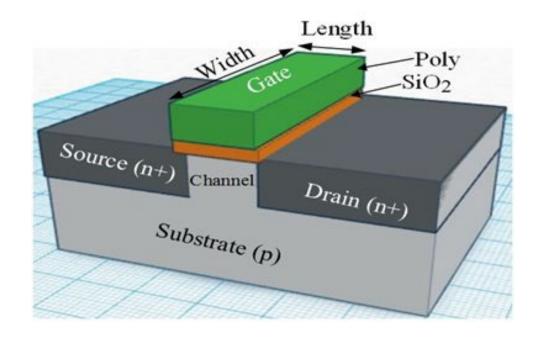
[Freitas: 2008]

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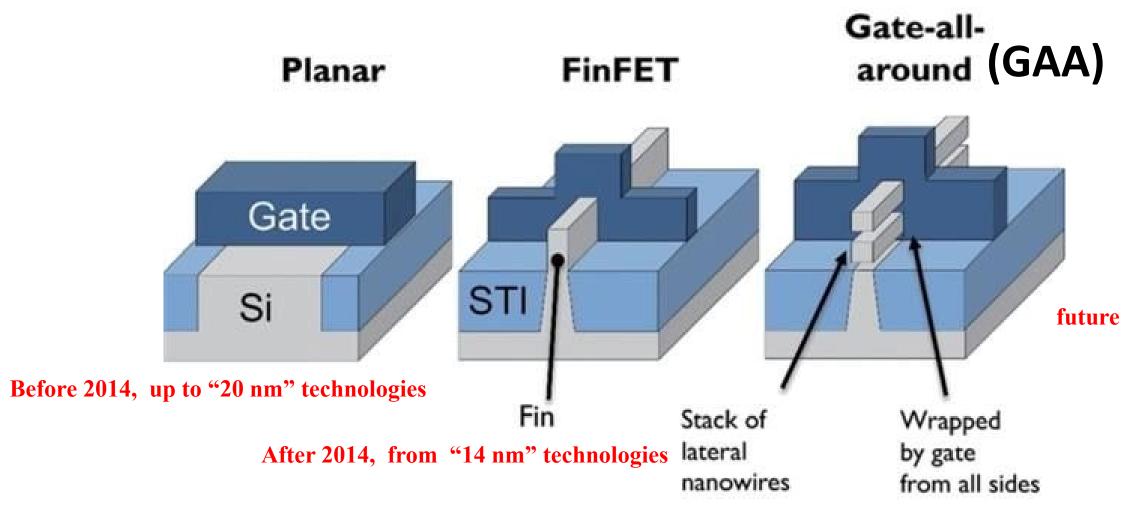
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# device shapes get more complex

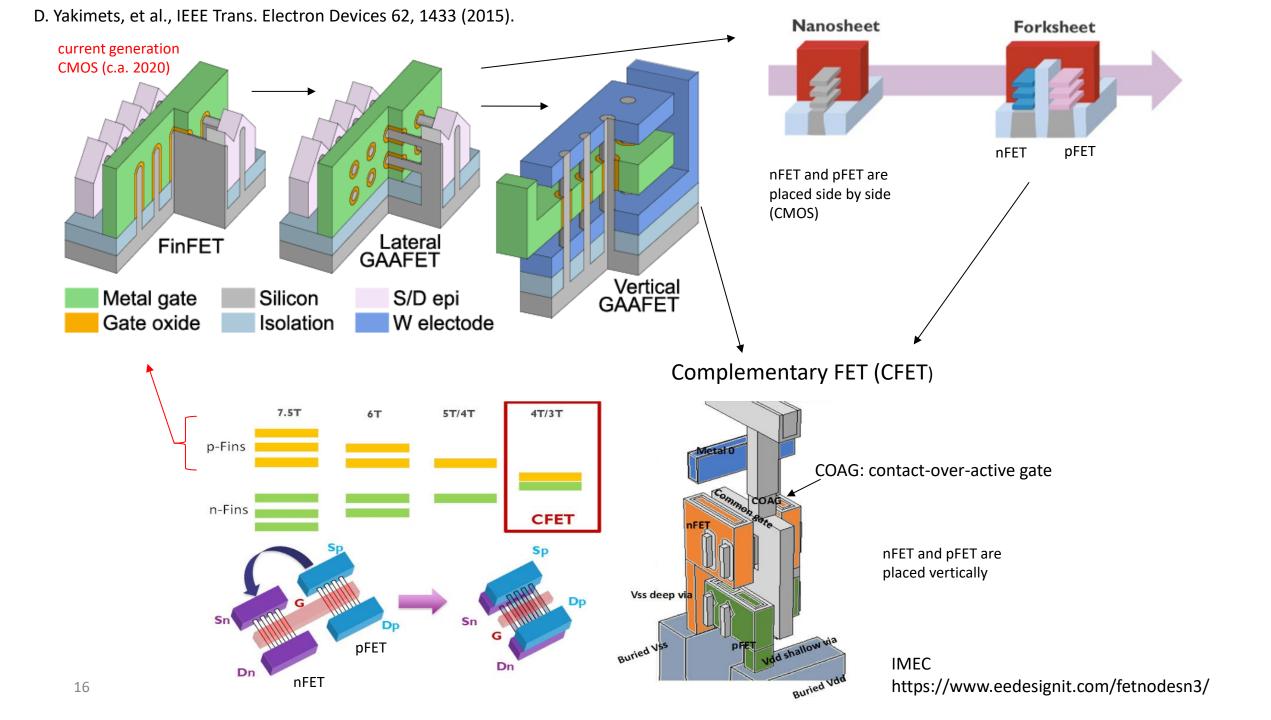


Before 2014, up to "20 nm" technologies

# device shapes get more complex



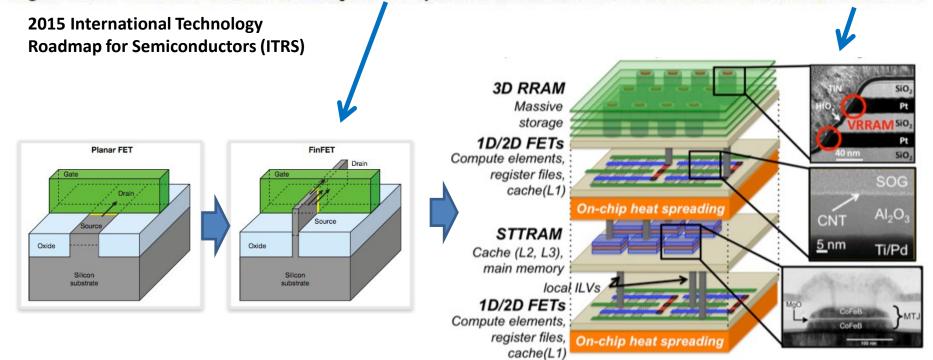
STI: shallow trench isolation



### **Development of Device Structures**

| YEAR OF PRODUCTION                        | 2015            | 2017            | 2019           | 2021                   | 2024         | 2027         | 2030      |
|---|-----------------|-----------------|----------------|------------------------|--------------|--------------|-----------|
| Logic device technology naming            | P70M56          | P48M36          | P42M24         | P32M20                 | P24M12G1     | P24M12G2     | P24M12G3  |
| Logic industry "Node Range" Labeling (nm) | "16/14"         | 711/107         | -817-          | -6/5-                  | -4/3-        | "3/2.5"      | "2/1.5"   |
| Lagia device structure aptions            | finFET<br>FDSOI | finFET<br>FDSOI | finFET<br>LGAA | finFET<br>LGAA<br>VGAA | YGAA,<br>M3D | YGAA,<br>M3D | VGAA, M3D |
|   | 200             | 254             | 244            | <b>-</b>               | 4            | <b>≥</b>     | <u></u>   |
|   | 240             | 140             | 200            | 242                    |              |              |           |
|   |                 | -               |                |                        |              |              |           |

Figure MM3: Transistor structure roadmap: FDSOI, finFET, lateral nanowire, vertical nanowire, and monolithic 3D.

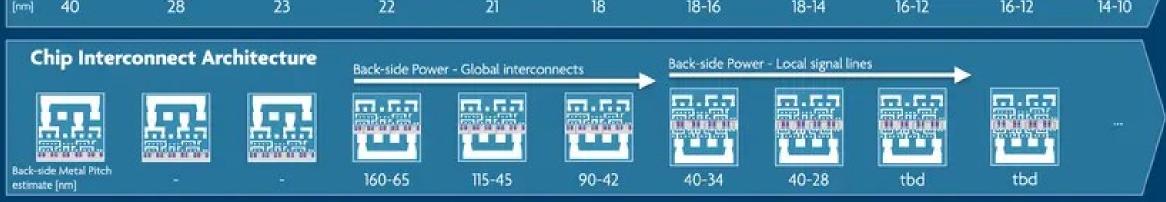


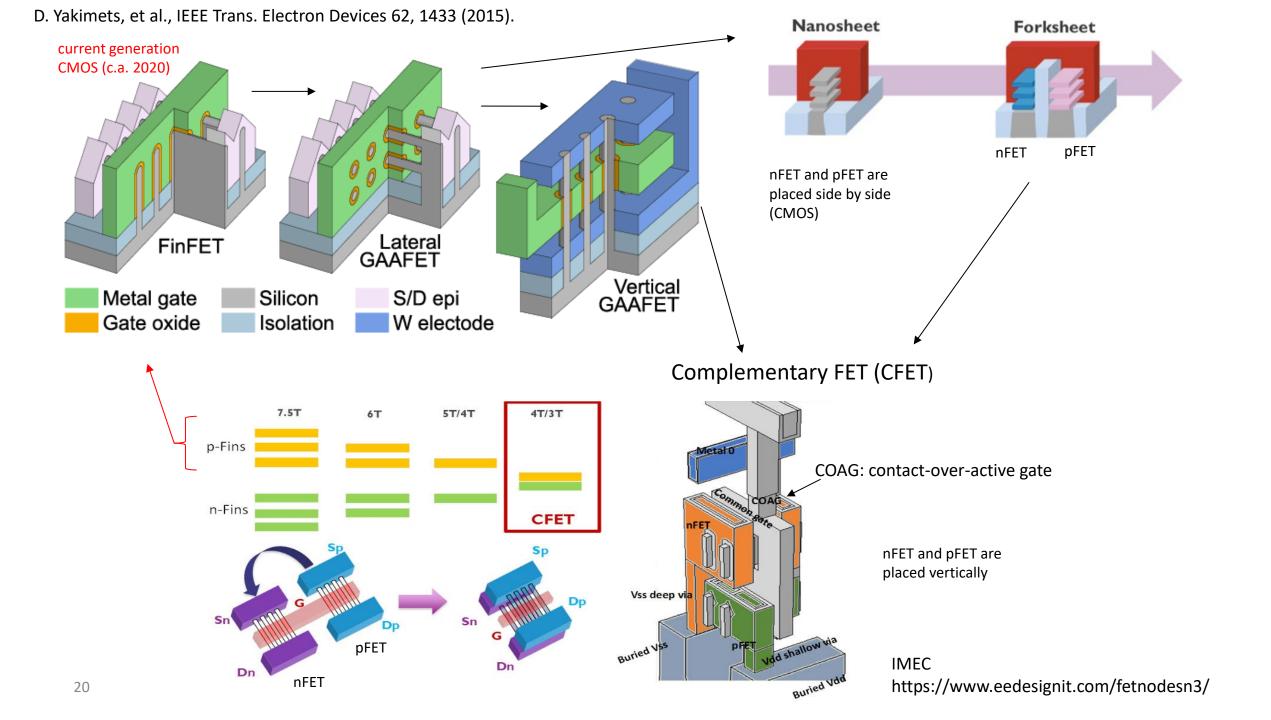
| YEAR OF PRODUCTION  | 2024           | 2025         | 2027           | 2029      | 2031           | 2033           | 2035           | 2037           | 2039           |
|---|----------------|--------------|----------------|-----------|----------------|----------------|----------------|----------------|----------------|
|   | G48M24         | G48M22       | G48M22         | G46M20    | G44M18         | G44M16         | G42M14/T2      | G42M14/T4      | G42M14/T6      |
| Logic industry "Node Range" Labeling                      | "3nm" Enhanced | "2nm"        | "1.4nm"        | "A10 eq"  | "A7 eq"        | "A5 eq"        | "A3.5 eq"      | "A2.5 eq"      | "A1.8 eq"      |
| Fine-pitch 3D integration scheme                          | Stacking       | Stacking     | Stacking       | Stacking  | CFET           | CFET           | 3DVLSI         | 3DVLSI         | 3DVLSI         |
| Logic device structure options                            | finFET         | LGAA         | LGAA           | LGAA      | CFET           | CFET           | CFET-3D        | CFET-3D        | CFET-3D        |
| Backside structure options                                | -              | Backside via | Direct contact | Decap+ESD | Active devices |
| Platform device for logic                                 | finFET         | LGAA         | LGAA           | LGAA      | CFET           | CFET           | CFET           | CFET           | CFET           |
|   |                |              |                |           |                |                | 72             | T4             | T6             |
| LOGIC DEVICE GROUND RULES                                 |                |              |                |           |                |                |                |                |                |
| Mx pitch (nm)   | 32             | 24           | 24             | 20        | 18             | 16             | 14             | 14             | 14             |
| M1 pitch (nm)   | 32             | 32           | 32             | 46        | 44             | 44             | 42             | 42             | 42             |
| M0 pitch (nm)   | 24             | 22           | 22             | 20        | 18             | 16             | 14             | 14             | 14             |
| Gate pitch (nm)   | 48             | 48           | 48             | 46        | 44             | 44             | 42             | 42             | 42             |
| Lg: Gate Length - HP (nm)                                 | 16             | 14           | 12             | 12        | 12             | 10             | 10             | 10             | 10             |
| Lg: Gate Length - HD (nm)                                 | 18             | 14           | 12             | 12        | 12             | 10             | 10             | 10             | 10             |
| Channel overlap ratio - two-sided                         | 0.20           | 0.20         | 0.20           | 0.20      | 0.20           | 0.20           | 0.20           | 0.20           | 0.20           |
| Spacer width (nm)   | 6              | 6            | 5              | 5         | 4              | 4              | 4              | 4              | 4              |
| Spacer k value  | 3.5            | 3.3          | 3.0            | 3.0       | 2.7            | 2.7            | 2.7            | 2.7            | 2.7            |
| Contact CD (nm) - finFET, LGAA                            | 20             | 22           | 26             | 24        | 24             | 26             | 24             | 24             | 24             |
| Device architecture key ground rules                      | 20             | EL.          | 20             | 24        | 24             | 20             | 24             | 24             | 24             |
| Device lateral pitch (nm)                                 | 24             | 26           | 24             | 24        | 22             | 22             | 22             | 22             | 22             |
| Device gate vertical overhang (nm)                        | 15             | 15           | 15             | 10        | 10             | 10             | 10             | 10             | 10             |
| Device gate vertical overhaing (IIII)  Device height (nm) | 48             | 57           | 72             | 64        | 75             | 62             | 60             | 53             | 53             |
| FinFET Fin width (nm)                                     | 5.0            | JI           | 12             | 04        | 13             | UZ.            | 00             | 33             | 33             |
| Footprint drive efficiency - finFET                       | 4.21           |              |                |           |                |                |                |                |                |
| Lateral GAA vertical pitch (nm)                           | 4.21           | 18.0         | 17.0           | 16.0      | 15.0           | 14.0           | 13.0           | 12.0           | 12.0           |
| Lateral GAA (nanosheet) thickness (nm)                    |                | 6.0          | 6.0            | 6.0       | 5.0            | 4.0            | 4.0            | 4.0            | 4.0            |
| Number of vertically stacked nanosheets on one device     |                | 3            | 4              | 4         | 3.0            | 3              | 3              | 3              | 3              |
|   |                | 30           | 20             | 12        | 30             | 25             | 20             | 15             |                |
| LGAA width (nm) - HP                                      |                |              | 10             | 6         | 30<br>15       | 12             | 10             | 15<br>8        | 12<br>8        |
| LGAA width (nm) - HD                                      |                | 15<br>7      | 6              | 6         | 6              | 6              | 6              | 6              | 6              |
| LGAA width (nm) - SRAM                                    |                |              |                |           |                |                | 4.00           |                |                |
| Footprint drive efficiency - lateral GAA - HP             | 404.0          | 4.41         | 5.47           | 4.80      | 4.57           | 4.24           |                | 3.68           | 3.43           |
| Device effective width (nm) - HP                          |                | 216.0        | 208.0          | 144.0     | 210.0          | 174.0          | 144.0          | 114.0          | 96.0           |
| Device effective width (nm) - HD                          | 101.0          | 126.0        | 128.0          | 96.0      | 120.0          | 96.0           | 84.0           | 72.0           | 72.0           |
| PN seperation width (nm)                                  | 45             | 40           | 30             | 20        |                |                |                |                |                |
| CFET PN seperation vertical space (nm)                    |                |              |                |           | 30             | 20             | 20             | 15             | 15             |

#### Device Architecture and Ground Rules Roadmap for Logic Devices.

Note: GxxMxx/Tx notation refers to Gxx: contacted gate pitch, Mxx: tightest metal pitch in nm, Tx: number of tiers. This notation illustrates the technology pitch scaling capability. On top of pitch scaling there are other elements such as cell height, number of stacked devices, DTCO constructs, 3D integration, etc. that define the target area scaling (gates/mm2). LGAA—lateral gate-all-around-device (GAA), CFET (Complementary Field Effect Transistor), 3DVLSI—fine-pitch 3D logic sequential integration. (https://irds.ieee.org/images/files/pdf/2024/2024IRDS\_MM.pdf)

#### Options extending the roadmap unec 2027 2031 2018 2020 2023 2025 2029 2033 2035 2037 2039 A5 **N7** N5 N3 N2 **A14** A10 A7 A3 A2 sub-A2 Device and material innovations NanoSheet 2DFET, ?, ... **FinFET CFET** Scaled Introduction Scaled Introduction Scaled Introduction Introduction Extended Extended Extended Scaled E Metal -4 <4 6 <4 <4 Tracks. Continued dimensional scaling 0.33NA EUV 0.55NA EUV 0.75NA EUV ? Metal Pitch 23 22 18-14 28 21 18 18-16 16-12 16-12 14-10 40





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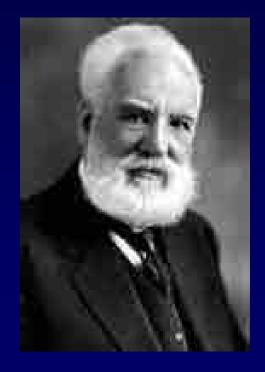
# Brief History of IC

How were the Semiconductor Industry and Silicon Valley born?

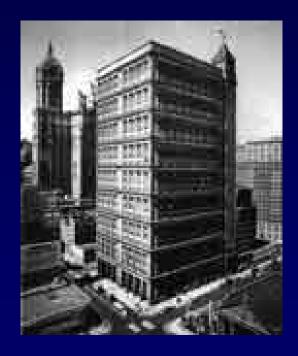
New technologies are driven by "Needs"

Necessity is the mother of invention (Plato)

- AT&T(America Telephone & Telegram) in the late 19 Century
- Monopoly of the telephone business due to the patent by Alexander Graham Bell (1876)



Alexander Graham Bell

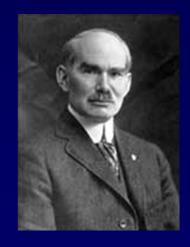


AT&T HQ in 1958

# Loss of telephone monopoly by AT&T

- Problem at 1894: AT&T
- Expiration of Bell's telephone patent: competition in the telephone business with other companies
- Problem at 1895: Bologna, Italy
- Invention of radio transmission by Guglielmo Marconi
- 1897: Establishment of Marconi Wireless Telegraph Company: the age of wireless telecommunication

- Strategy of AT&T (1907)
- Plan to build the first transcontinental phone line
- Problem: signal needs to be amplified
- Solution: bought the patent of a triode vacuum tube by Lee De Forest (1906) and started to develop amplifiers.



American Inventor: Lee De Forest



- •1909: Announcement by Vail (president of AT&T) of the plan to build the first transcontinental telephone line
- •1914: Completion of the transcontinental line



Theodore Vail (President of AT&T) making long-distance phone call, 1915, Courtesy AT&T

- 1925: Bell Laboratories became a subsidiary company of AT&T (number of employees = 3,600, annual budget 12 million dollars: the largest R&D organization in the US by then)
- Objectives: to solve all technical problems for telephone lines in the US

MURRAY HILL, NJ - MARCH 13, 1942: Bell Telephone Laboratory, Murray Hill, New Jersey. Main group from acoustics laboratory roof. Gottscho-Schleisner, Inc./Courtesy Library of Congress Prints and Photographs Division Washington, D.C., call no. LC-G612- 42005



- Big Problem of telephone lines then: vacuum tubes have low reliability and large power consumption
- In 1936, Mervin Kelly became Research Director of Bell Laboratories and, after the WWII, formed a Solid State Physics group (led by W. Shockley) to develop solid-state amplifiers.

- In the Solid State Physics Group of Bell Labs led by William Shockley, experimentalist Walter Brattain and theorist John Bardeen invented a transistor. The Nobel Prize in Physics was granted to Bardeen, Brattain, and Shockley in 1956.
  - The team applied quantum mechanics, which was just born in the 1930s, to the development of solid-state devices



pnp point-contact germanium transistor



Bardeen, Shockley, and Brattain

- AT&T replaced all vacuum-tube-based signal amplifiers with those with transistors in the 1950s and made the system work without switchboard operators.
- Transistors are in high demand for military use:
  - US semiconductor companies did not show much interest in civilian applications.

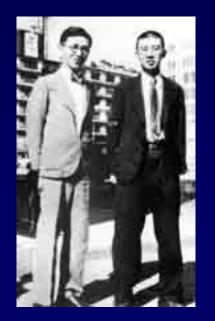


The first commercial transistor (1949)

The first transistor radio
Regency T1 (1954)
(Co-produced by Regency and
Texas Instrument)



Despite its very successful sales, the company stopped production in 1955 in order to focus on other products.



Tokyo Telecommunication Engineering Co. (which later became SONY) entered the US market for transistor radios after the retreat of T1 and became very successful.

Masaru Ibuka, left, with Akio Morita, Sony Corp.

### Birth of Silicon Valley

• In 1955, Shockley left Bell Labs and established Shockley Semiconductor in Mountain View, Ca, to develop and manufacture new semiconductor devices.

• In 1957, 8 young scientists ("the Traitorous Eight") left Shockley Semiconductor and established Fairchild Semiconductor.

• In 1960, Shockley Semiconductor was bought by Clevite Transistor.

# Invention of IC (Integrated Circuits)

- In 1957, 8 former Shockley Semiconductor scientists established Fairchild Semiconductor. The 3rd company in the current Silicon Valley.
- In 1959, Robert Noyce of Fairchild Semiconductor invented ICs. (The first IC patent in 1961)
- Around the same time (1958), Jack Kilby of Texas Instruments (TI) independently invented IC.



The first IC of TI

### Fairchild Semiconductor & Intel

- Fairchild Semiconductor grew rapidly in the business of developing and manufacturing ICs. The number of employees grew from 12 to 12,000.
- Noyce introduced Californian style management: casual atmosphere in business.
- Many of co-founders of Fairchild Semiconductor left the company and built their own companies, which became the base of the present-day Silicon Valley. (Fairchildren)
- In 1968, Robert Noyce and Gordon Moore left Fairchild and founded Intel.
- Other include National Semiconductors and Advanced Micro Devices.

# Success of Transistors & IC development

- Needs  $\rightarrow$  long-distance telephone line solid-state devices
- Method of development
  - The latest theory of fundamental science (quantum mechanics)
  - Systematic search of materials
- Development of the market
  - Technological innovation (e.g., invention of IC) and market development by Fairchild & Intel

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# Types of Semiconductors



#### Memory

SoCs

Combines other chips onto one chip. Include memory, CPU, and GPU

#### NAND DRAM



Volatile Memory loses data when power is lost.



Memory, slower & stores less data



Processes many tasks at once. Well suited for graphics and AI.

**GPUs** 





Designed for one specific purpose. AI accelerators for example.

#### **CPUs**



Gives directions to other chips. Processes one task at a time.

#### **FPGAs**



Can be reprogrammed after manufacturing.

#### Analog



Processes continuous signals such as temperature, sound, and light

#### Signal

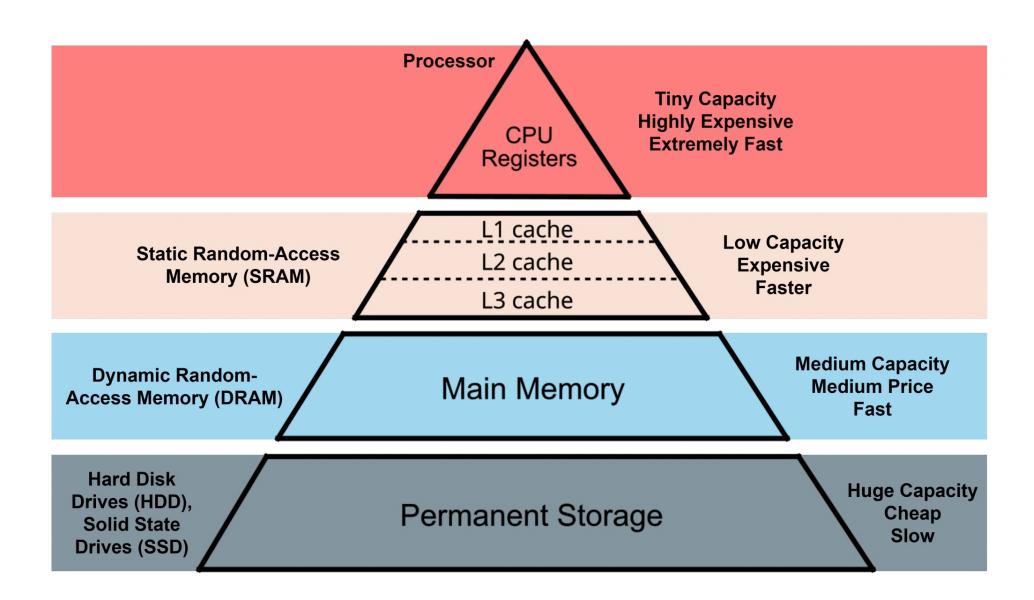


Measure real-world signals & convert to data

#### Power

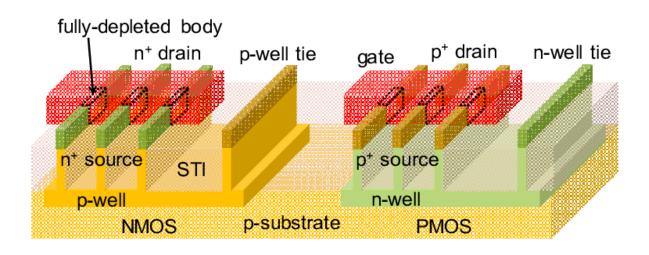


Manages power in electronics: switches, battery managment

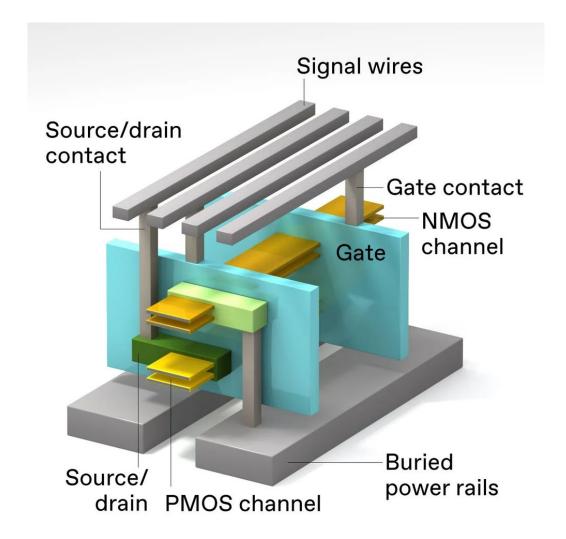


#### **Future CMOS? 3D-stacked CMOS**

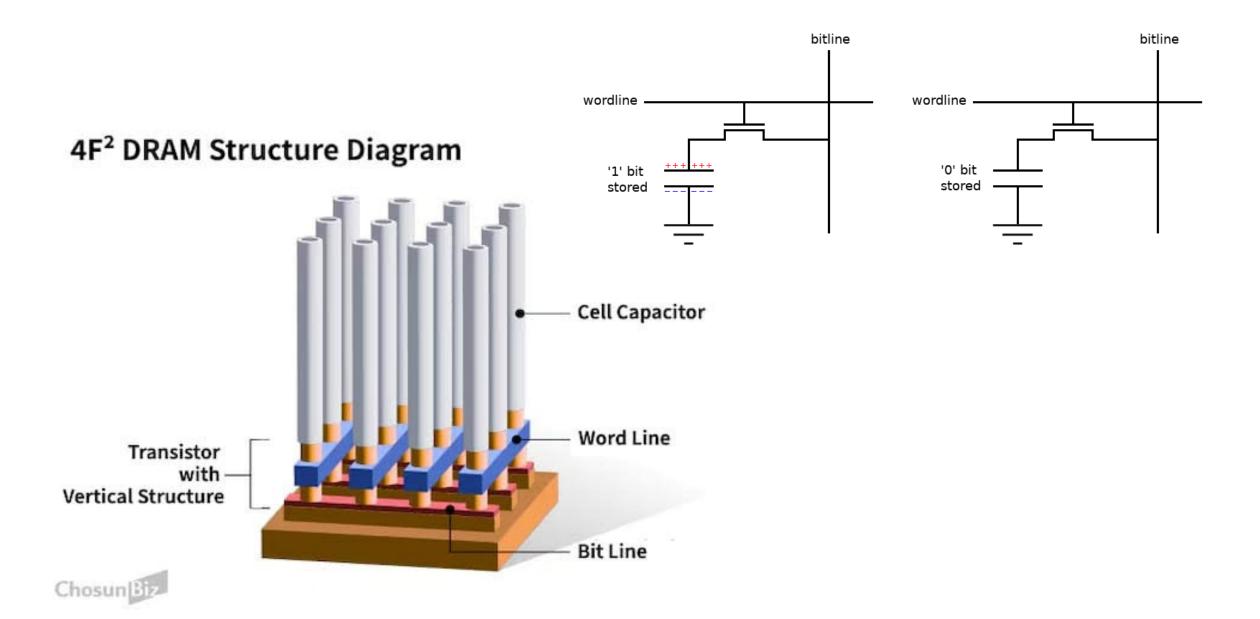
# FinFET CMOS: current generation



https://www.researchgate.net/publication/324608238/figure/download/fig1/AS:617287212097542@1524184148757/Fully-depleted-bulk-CMOS-finFETs.png



https://spectrum.ieee.org/media-library/orange-elongated-blocks-connect-to-several-narrower-blocks-of-a-variety-of-colors.jpg?id=30542266&width=1000&quality=85



**3D NAND Flash memory** 



https://dmassets.micron.com/is/image/microntech nology/nand-flash-worlds-first-layers%3A3-2-allothers?ts=1750894890969&dpr=off

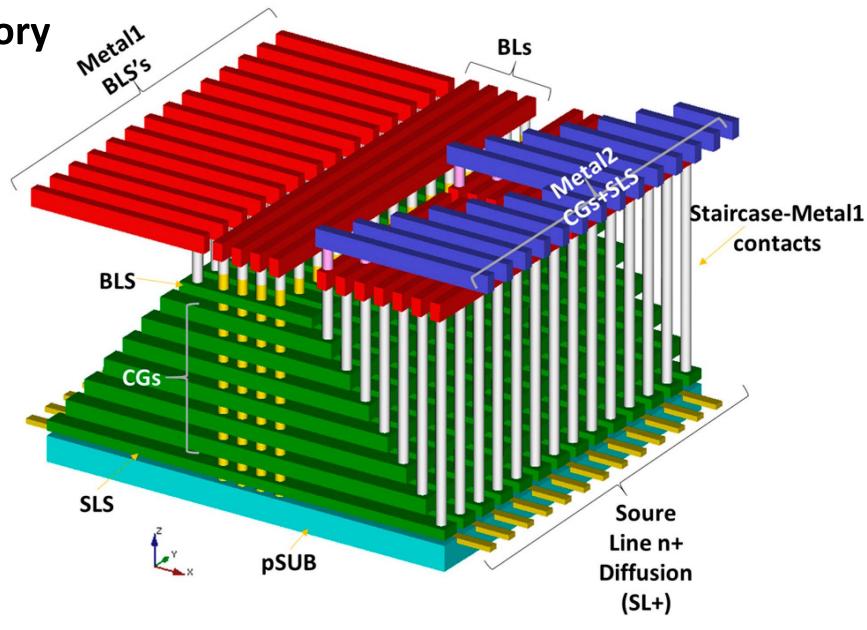
BLS: bit line selector

SLS: source line selector

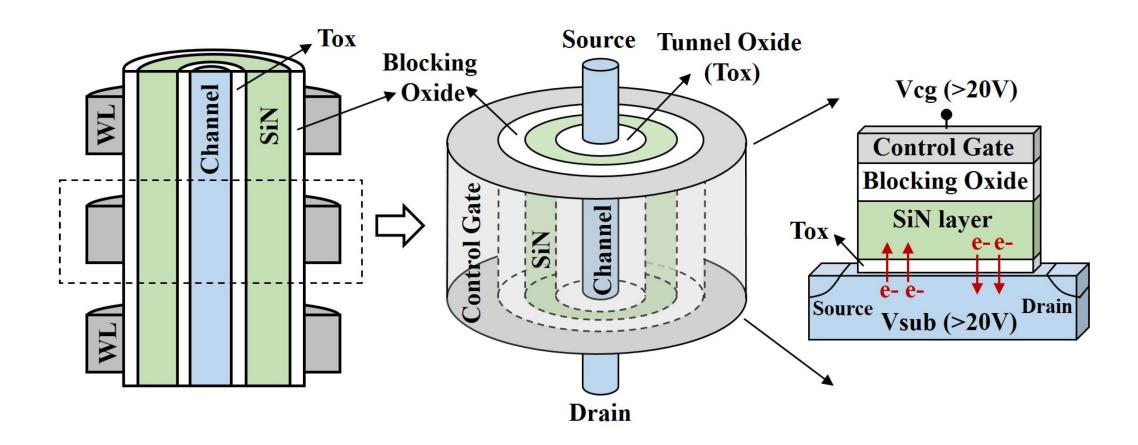
CG: control gate (word line)

BL: bitline

pSUB: p-type substrate



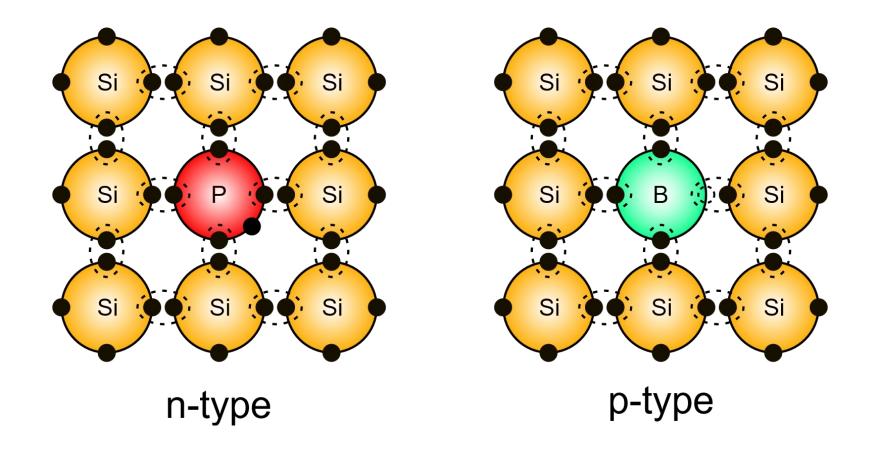
# 3D NAND Flash memory: memory cell



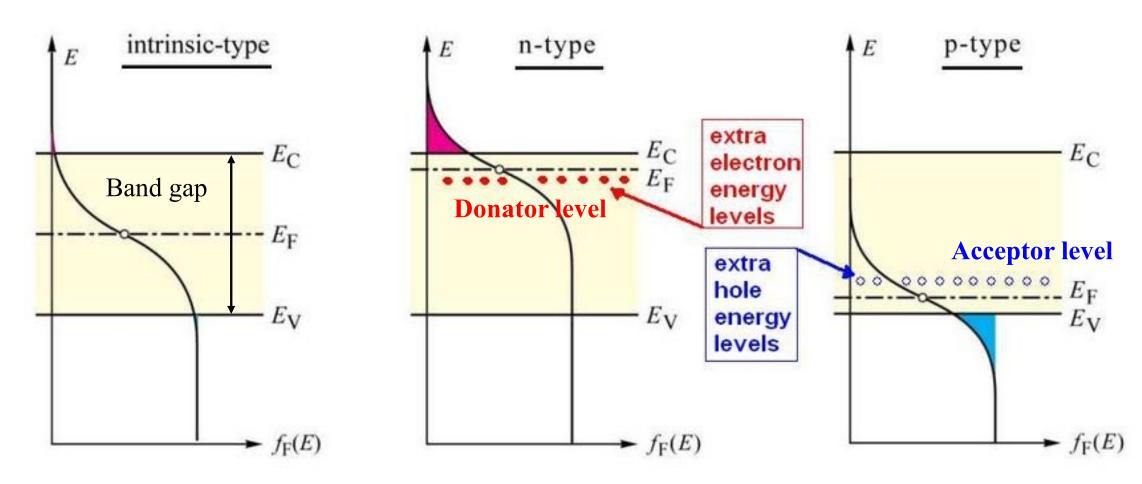
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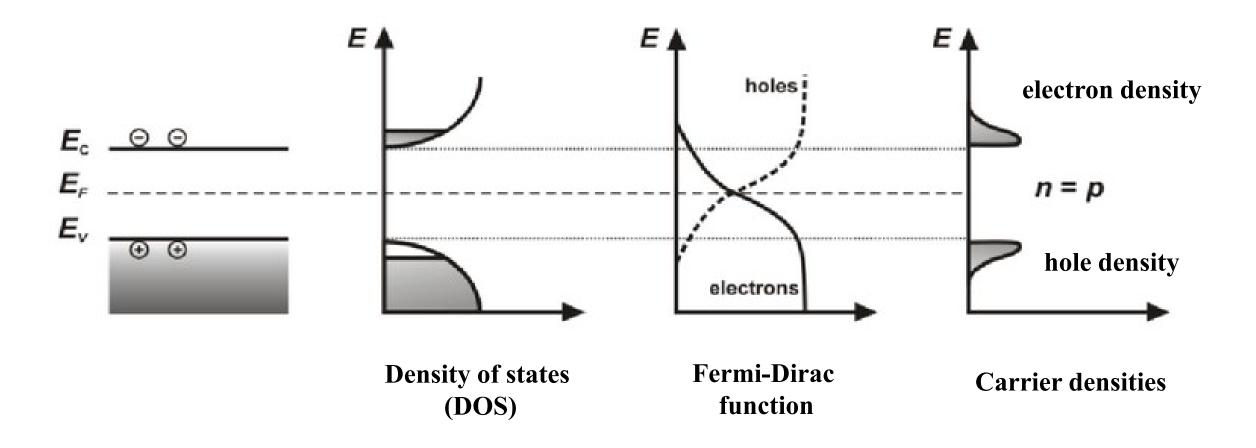


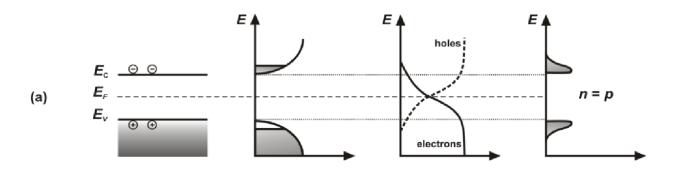
#### $f_{\rm F}(E)$ : Fermi-Dirac distribution function

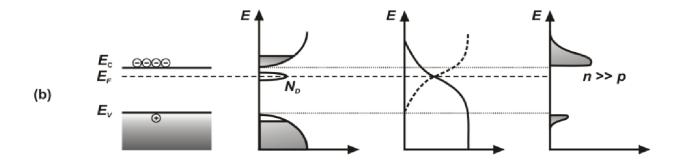


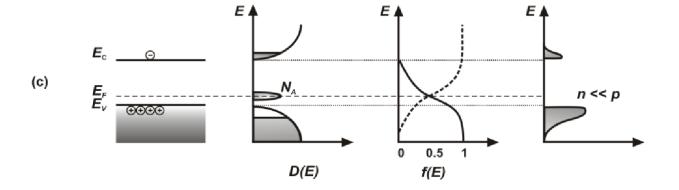
 $E_c$ : conduction band energy,  $E_F$ : Fermi energy,  $E_V$ : Valence band energy

## For Intrinsic Si (i.e., without dopants)

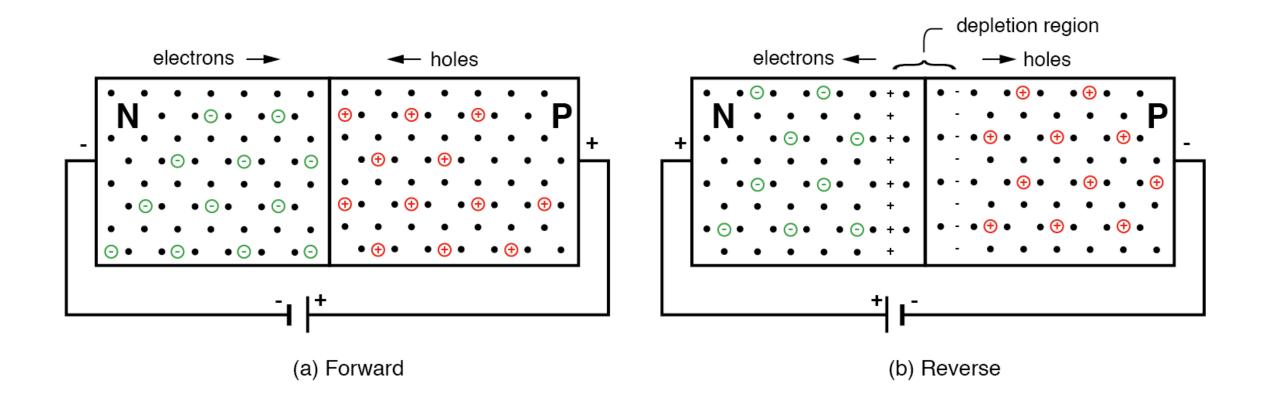






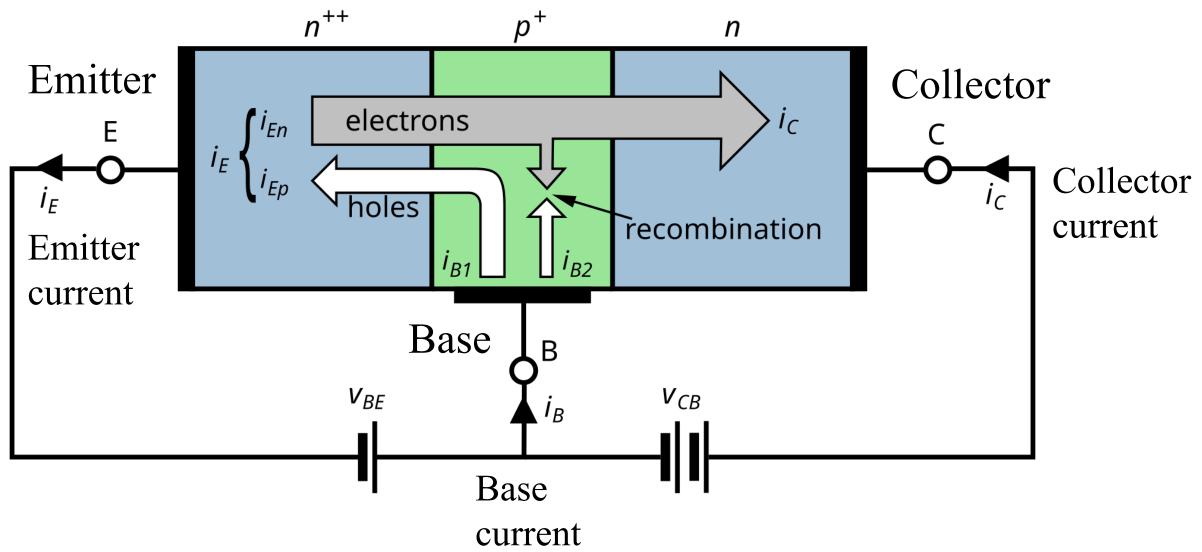


## PN junction diode

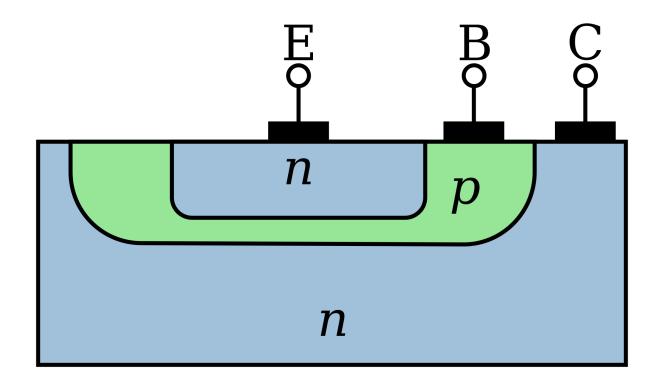


https://www.allaboutcircuits.com/uploads/articles/pn-junction-bias.png

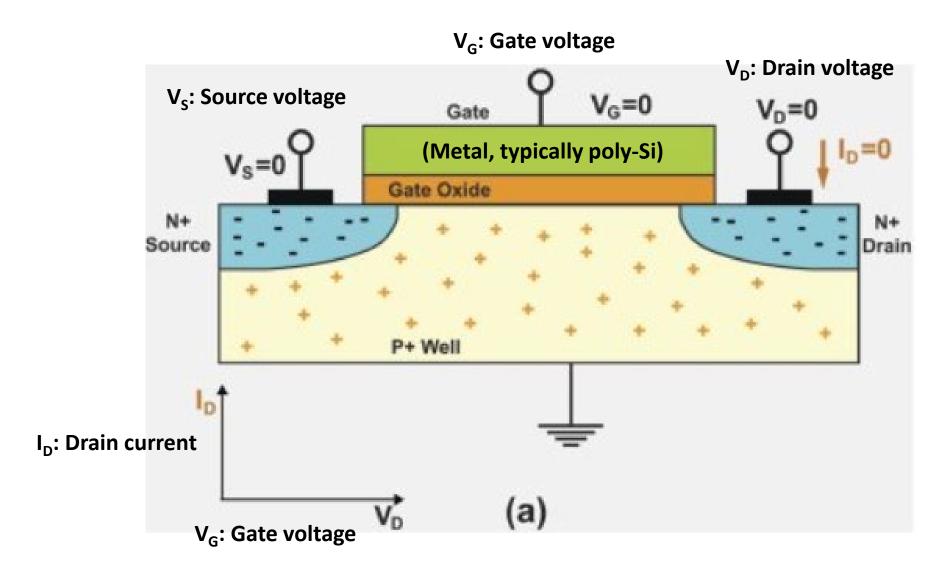
## Bipolar Junction Transistor (BJT): NPN transistor

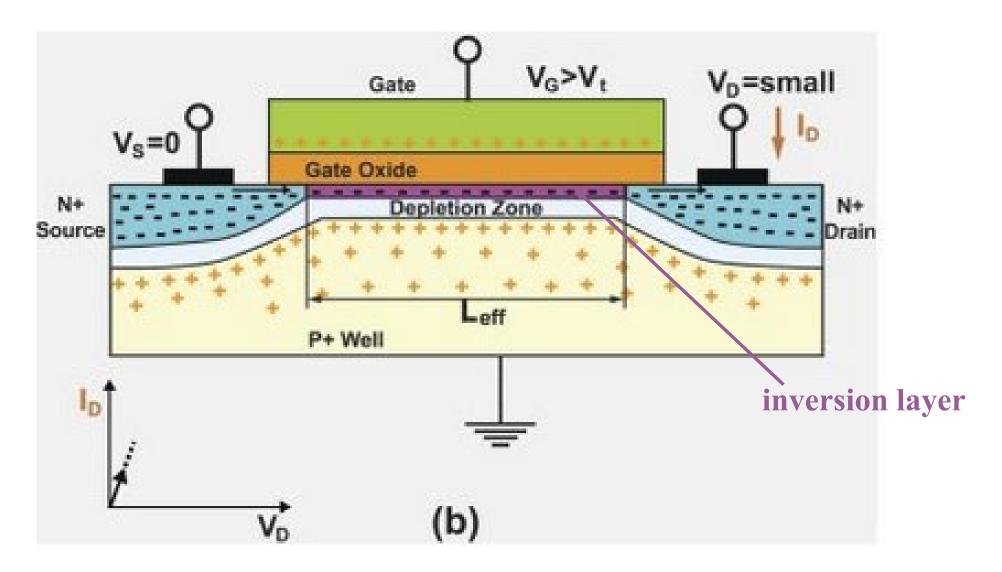


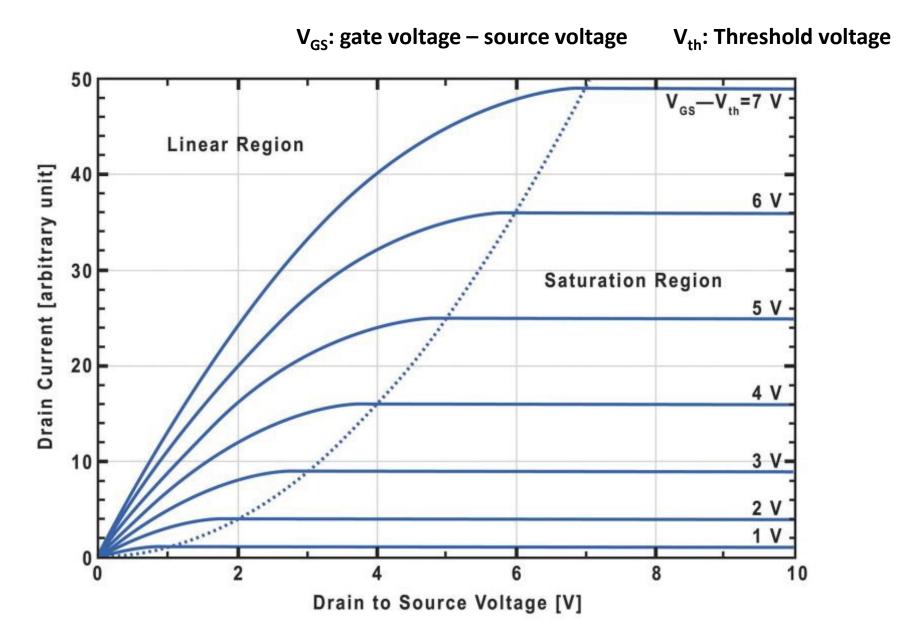
### Bipolar Junction Transistor (BJT): NPN transistor

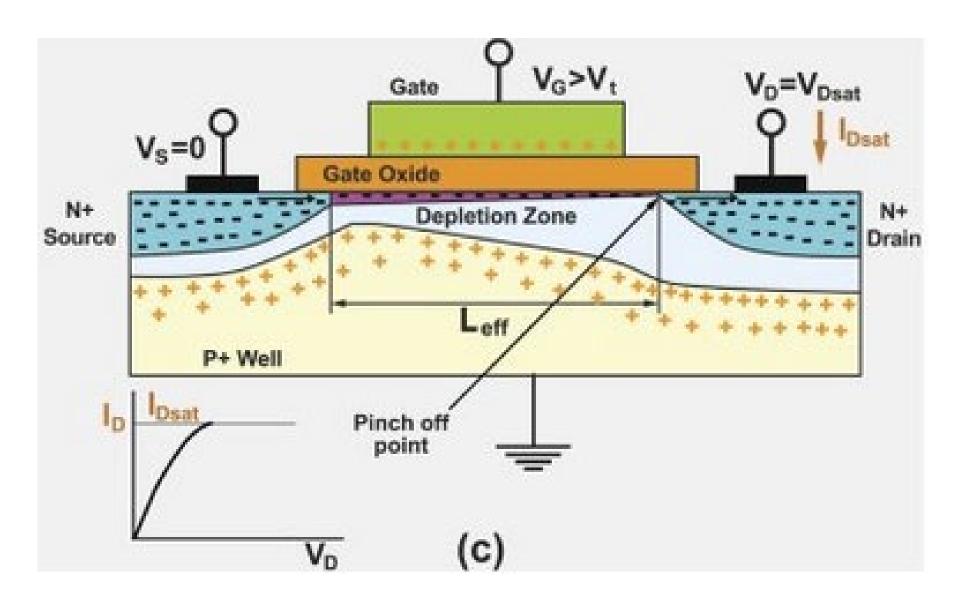


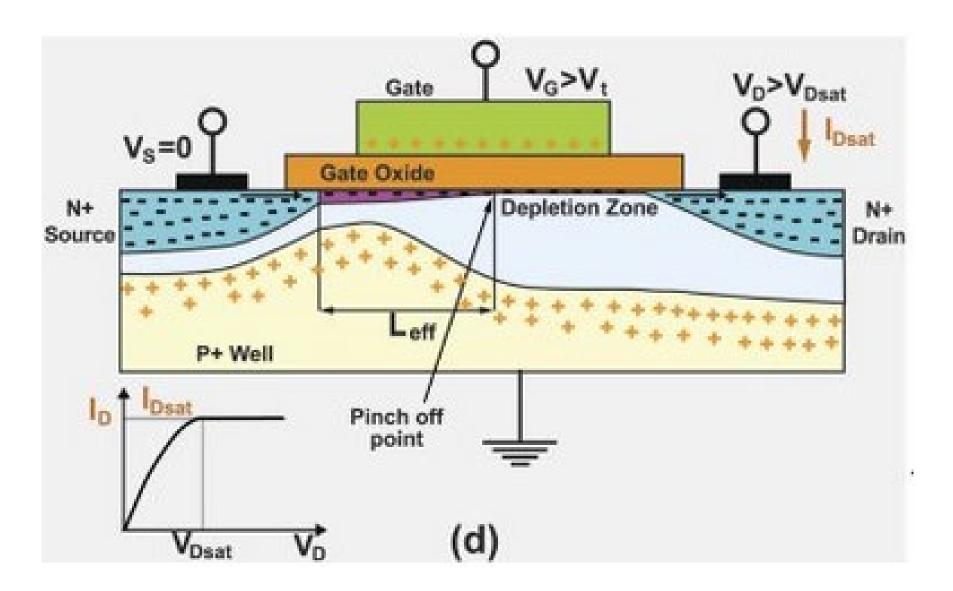
Simplified cross section of a planar NPN bipolar junction transistor







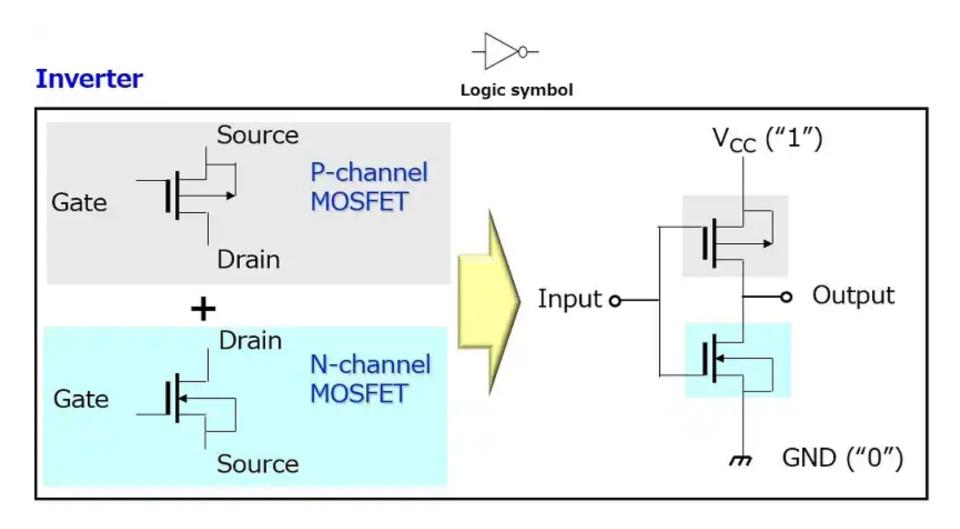




#### **PMOS NMOS** Source Gate Drain Source Gate Drain Metal Gate Metal Gate Metal Metal Metal Metal Contact Contact Contact Contact n-type n-type p-type p-type p-type n-type Gate Oxide Gate Oxide Bulk Bulk (a) (b)

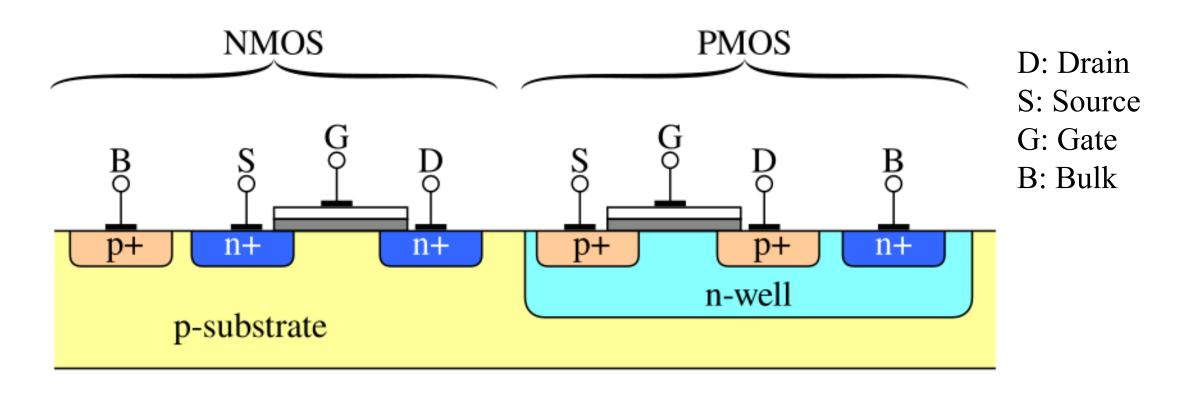
MOS consumes much less power than BJT

## **Complementary MOS FET (CMOS)**

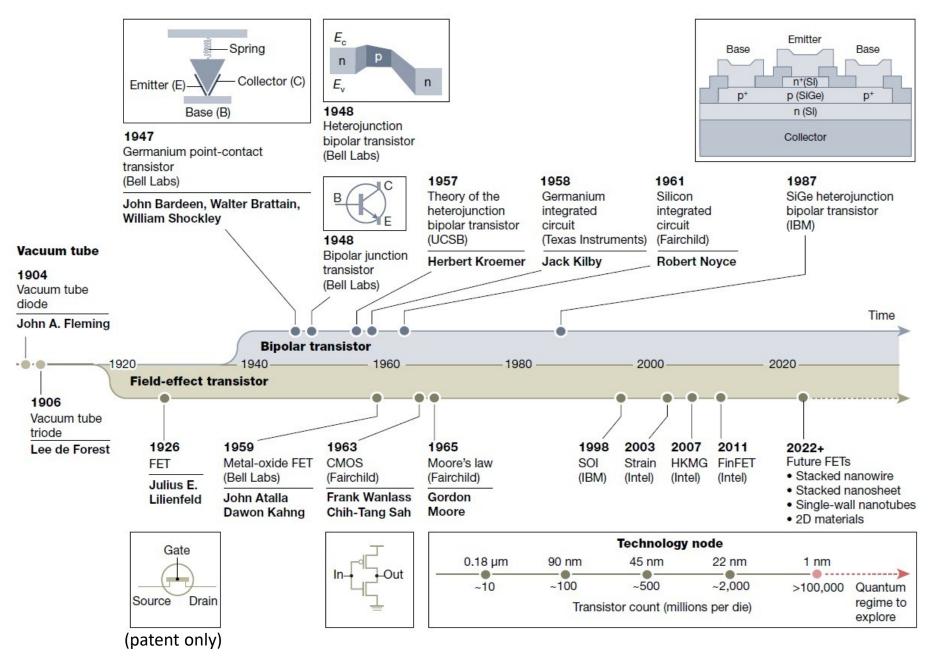


https://toshiba.semicon-storage.com/content/dam/toshiba-ss-v3/master/en/semiconductor/knowledge/e-learning/cmos-logic-basics/chap2-1\_en.jpg

#### **Complementary MOS FET (CMOS)**



The advantages of CMOS over NMOS or PMOS are lower power consumption, less prone to noise, and therefore, allow higher integration.



# Outline

- 1. The semiconductor industry
  - overview
  - technology roadmap
  - brief history
- 2. Outline of chip products: logic, memory, storage
- 3. Fundamentals of device physics
- 4. Fundamentals of Chip Manufacturing
  - Front-end processes (FEOL & BEOL)
  - Back-end processes
- 5. Summary

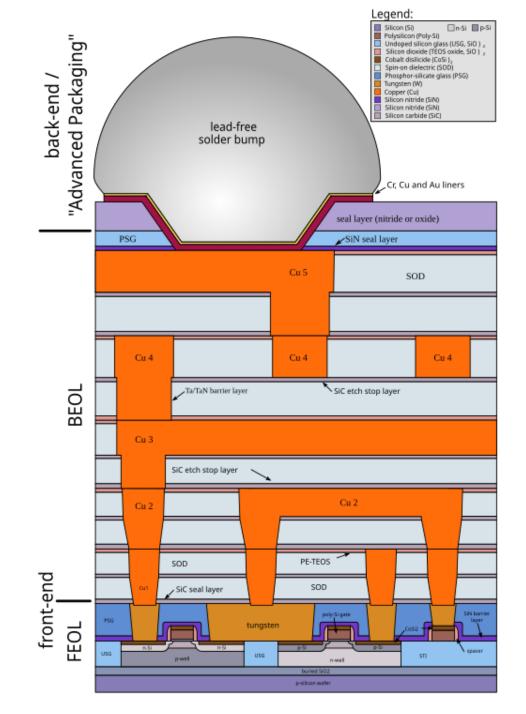
# Outline of semiconductor manufacturing

Cross-section of a chip  $\Rightarrow$ 

front-end processes

front end of line (FEOL)
back end of line (BEOL)

back-end processes



https://upload.wikimedia.org/wikipedia/commons/thumb/e/ee/Cmoschip\_structure\_in\_2000s\_%28en%29.svg/500px-Cmoschip\_structure\_in\_2000s\_%28en%29.svg.png

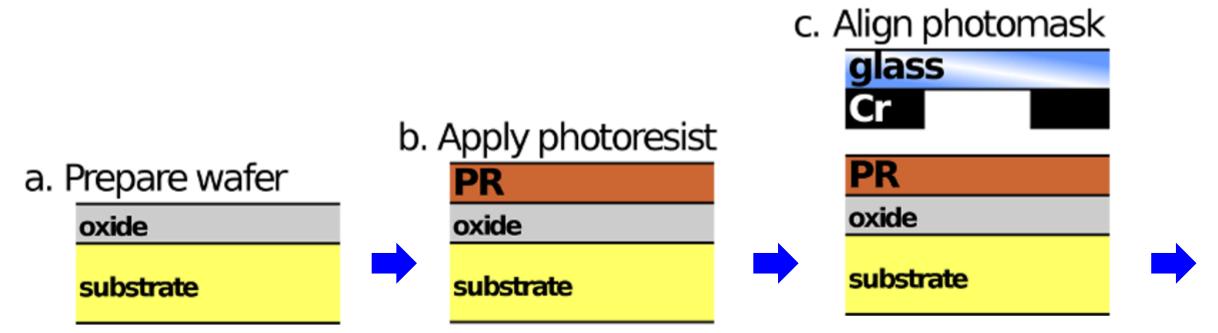
# **FOEL processes**

FEOL processes: the first portion of IC fabrication where the individual components (transistors, capacitors, resistors, etc.) are patterned in a semiconductor substrate. FEOL generally covers everything up to (but not including) the deposition of metal interconnect layers.

(https://en.wikipedia.org/wiki/Front\_end\_of\_line)

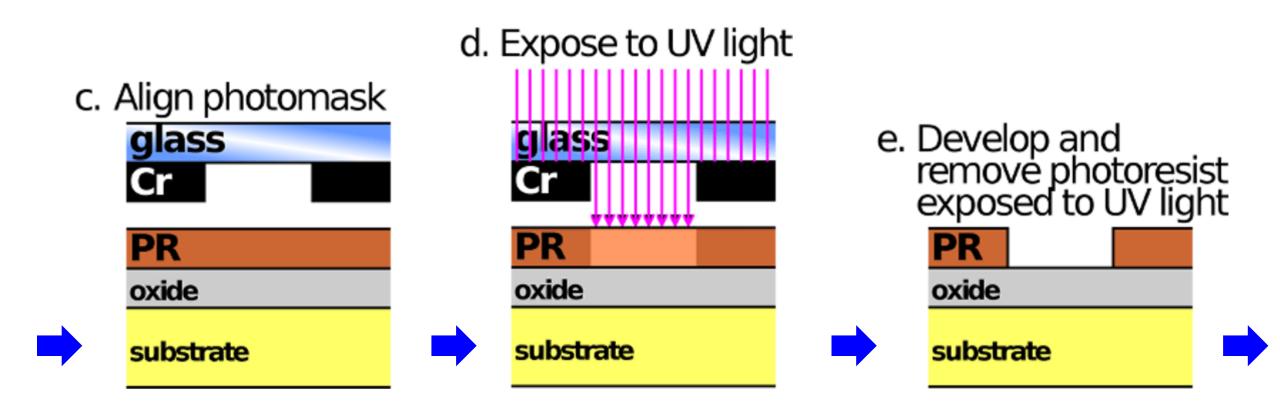
#### **Basic Pattern Formation Process**

How to form a mask for plasma etching



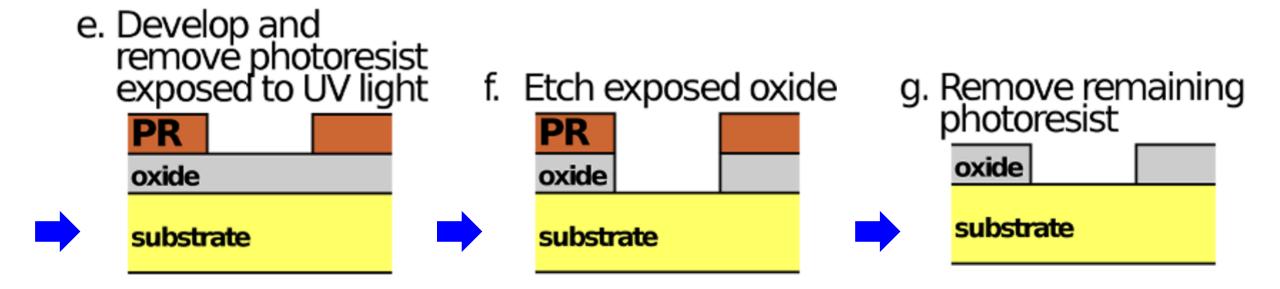
#### **Basic Pattern Formation Process**

How to form a mask for plasma etching

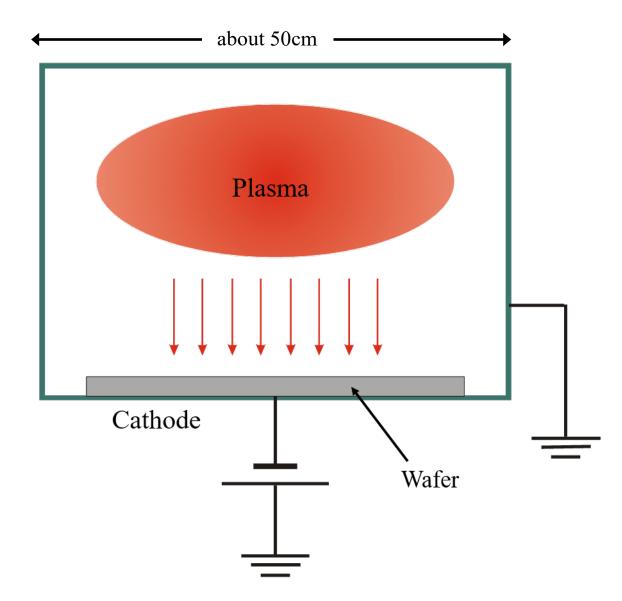


#### **Basic Pattern Formation Process**

How to form a mask for plasma etching

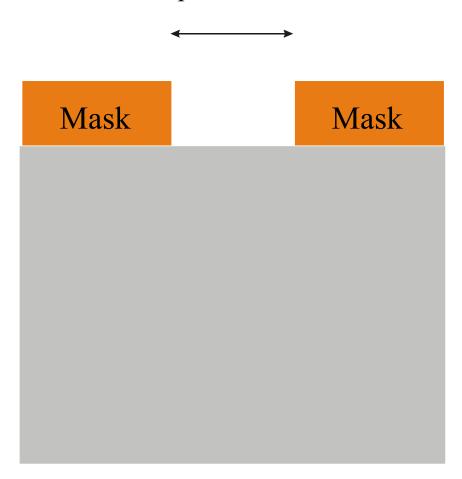


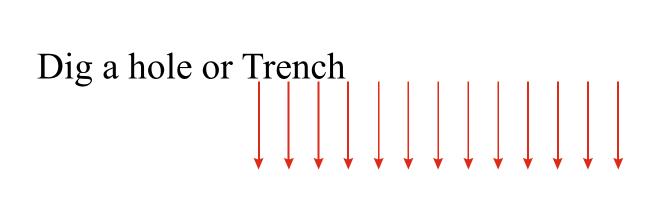
## Typical Plasma Processing Equipment

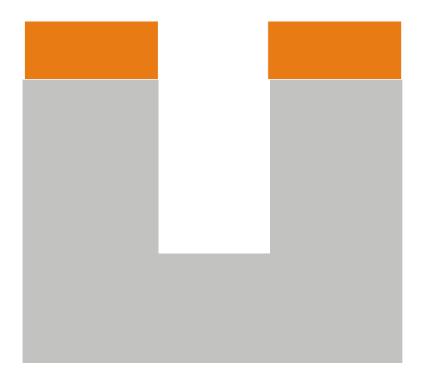


# Chip Surface

For example, about 100 nm



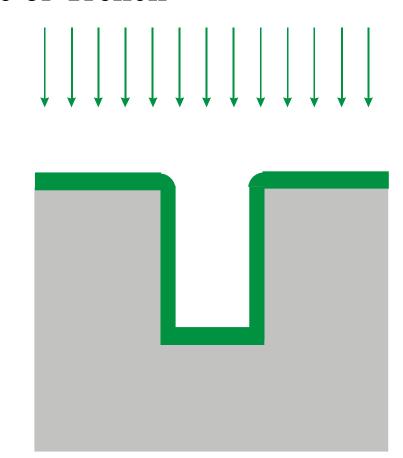




## Remove the masks

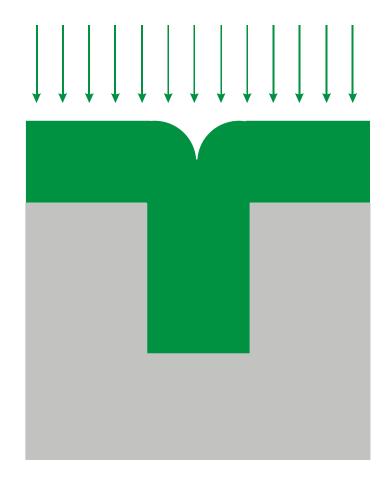


Fill the Hole or Trench

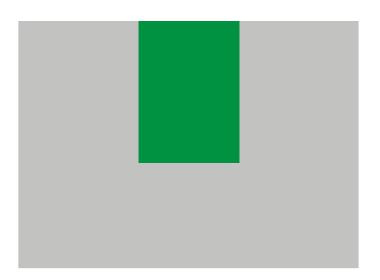


by Chemical Vapor Deposition (CVD) or Sputtering Deposition (Physical Vapor Deposition: PVD)

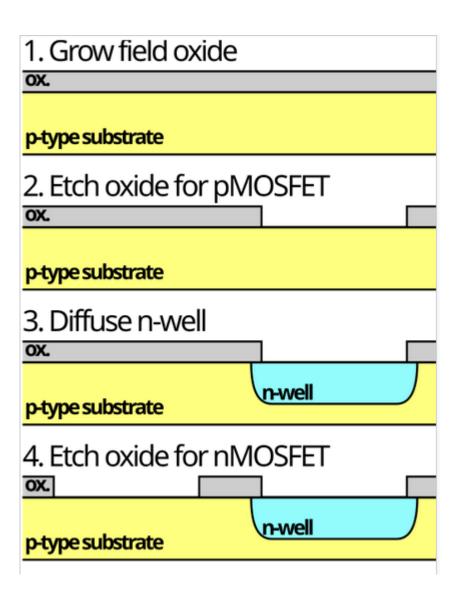
Fill the Hole or Trench



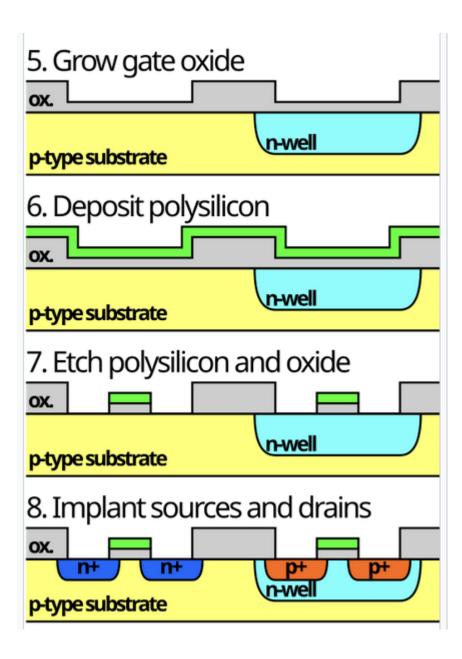
# Planarize by Chemical Mechanical Polish (CMP)

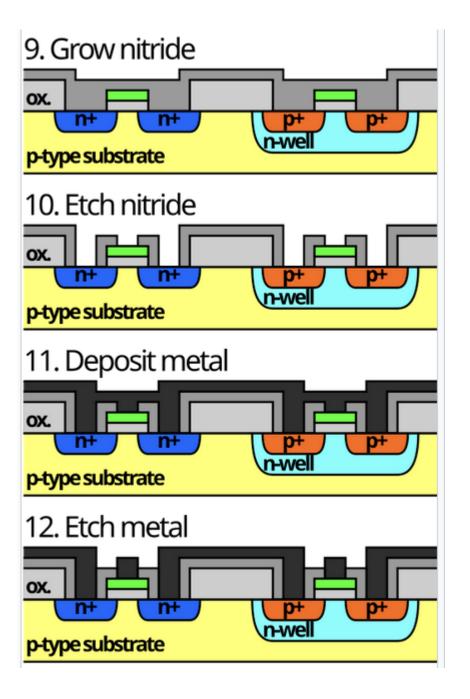


## Typical CMOS fabrication process



**⇐** ion implantation





← W deposition: CVD

(for higher layers, Cu is used via electrochemical deposition; damascene process)

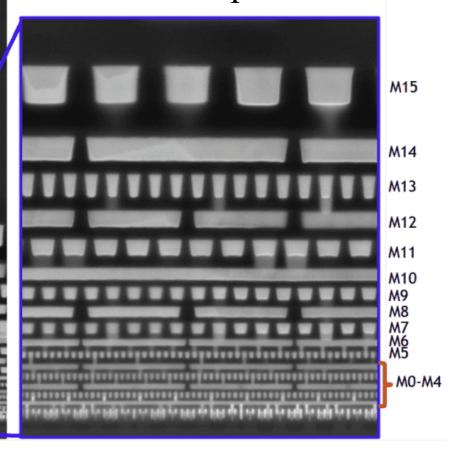
### **BOEL** processes

BEOL processes: the process in semiconductor device fabrication that consists of depositing metal interconnect layers onto a wafer already patterned with devices. It is the second part of IC fabrication, after FEOL. In BEOL, the individual devices (transistors, capacitors, resistors, etc.) are connected to each other according to how the metal wiring is deposited. (https://en.wikipedia.org/wiki/Back\_end\_of\_line)

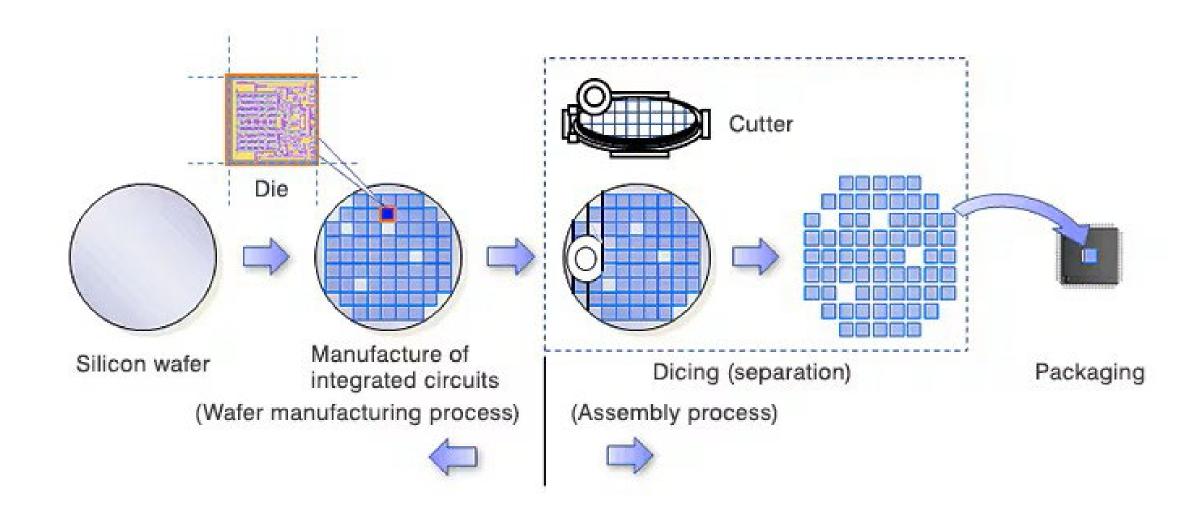
⇒ mostly Metalization processes

## **BOEL** processes

Metalization processes: deposition of metal wires and insulators



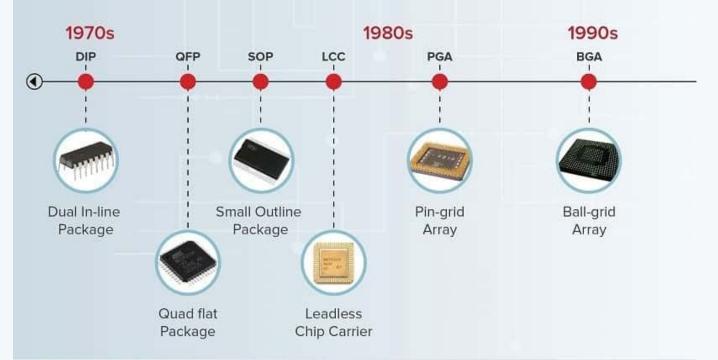
RC delay: the main factor that determines the chip's operation speed



Backend processes = Assembly, Testing, Packaging (ATP)

ATP = The last production stage of semiconductor chips, where individual chips are cut from the wafers, tested, assembled, packaged, and connected with wires that can be attached to the printed circuit board (PCB). This process is often outsourced to different companies.

(https://www.semiconductors.org/wp-content/uploads/2018/09/Assembly-Packaging.pdf)





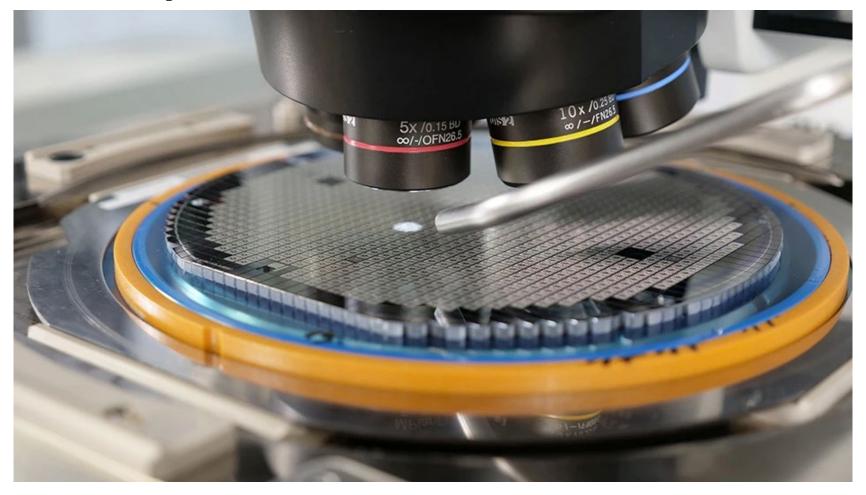
https://anysilicon.com/wpcontent/uploads/2016/02/Semicondcutorpackaging-history-doubled.jpg

## Summary of ATP

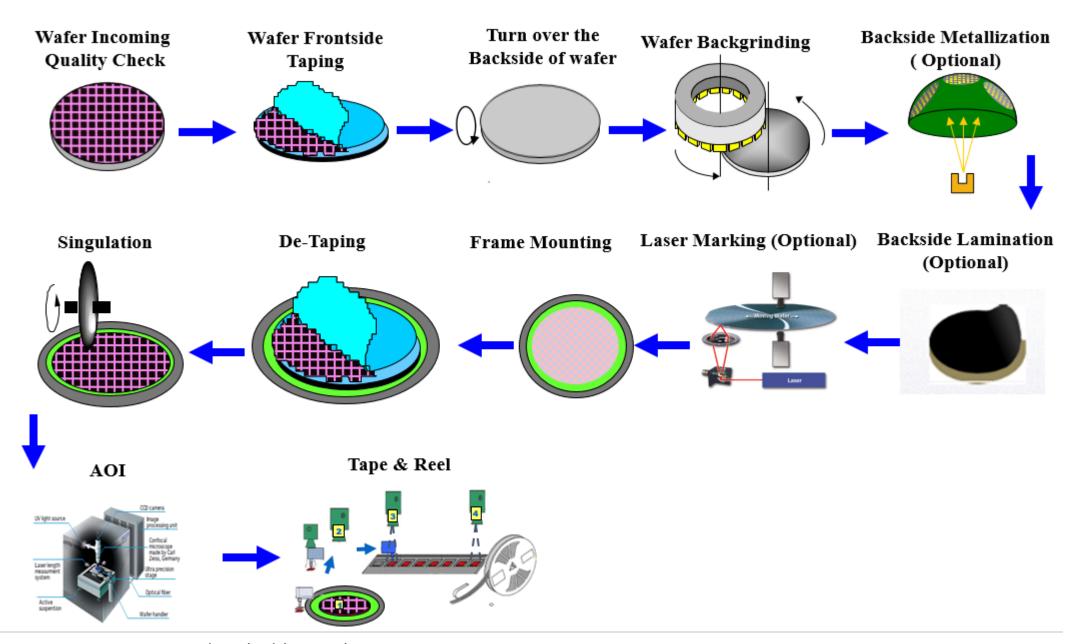
- Inspection
- Backgrinding
- Dicing
- Die bonding (die: a chip cut from a large wafer)
- Wire bonding or flip chip bonding
- molding
- Final Test

# inspection

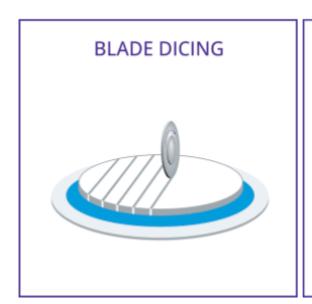
#### Automated inspection of a diced wafer

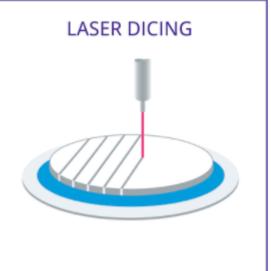


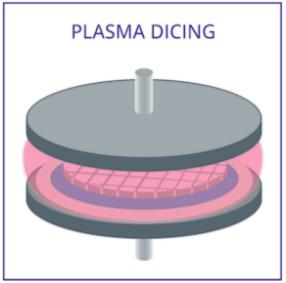
https://www.evdesignandmanufacturing.com/remote/aHR0cHM6Ly9naWVjZG4uYmxvYi5jb3JlLndpbmRvd3MubmV0L2ZpbGV1c GxvYWRzL2ltYWdlLzlwMjQvMDgvMTMvcHZhdGVwbGFfd2FmZXItc2F3aW5nLWluc3BlY3Rpb24tbWljcm9zY29wZTltLmpwZw.aorr M-ohSpw.jpg?format=webp



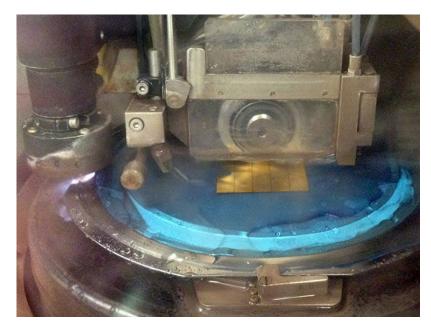
AOI: automated optical inspection



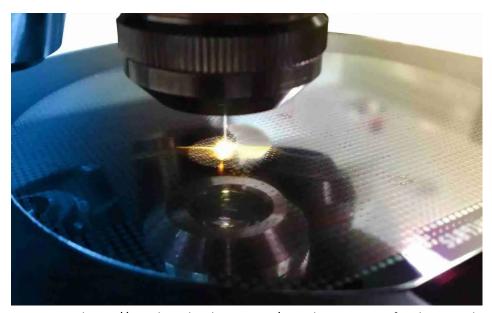




https://www.kla.com/advance/innovation/plasma-dicing-101-the-basics

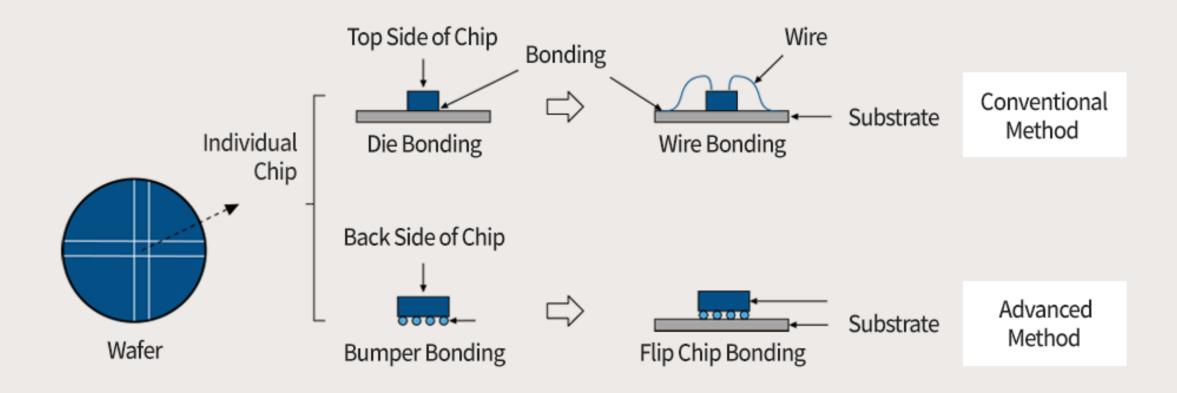


https://lnf-wiki.eecs.umich.edu/wiki/Dicing

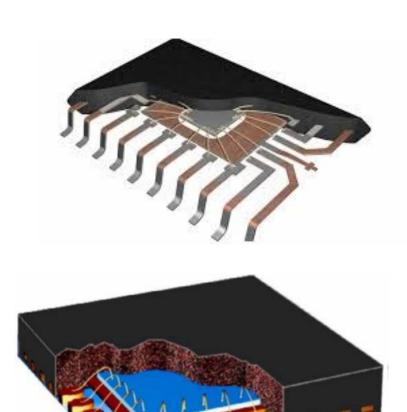


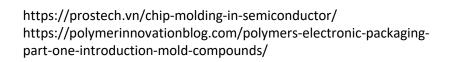
https://intech-technologies.com/introduction-to-wafer-dicing-techniques-2/

## Die bonding



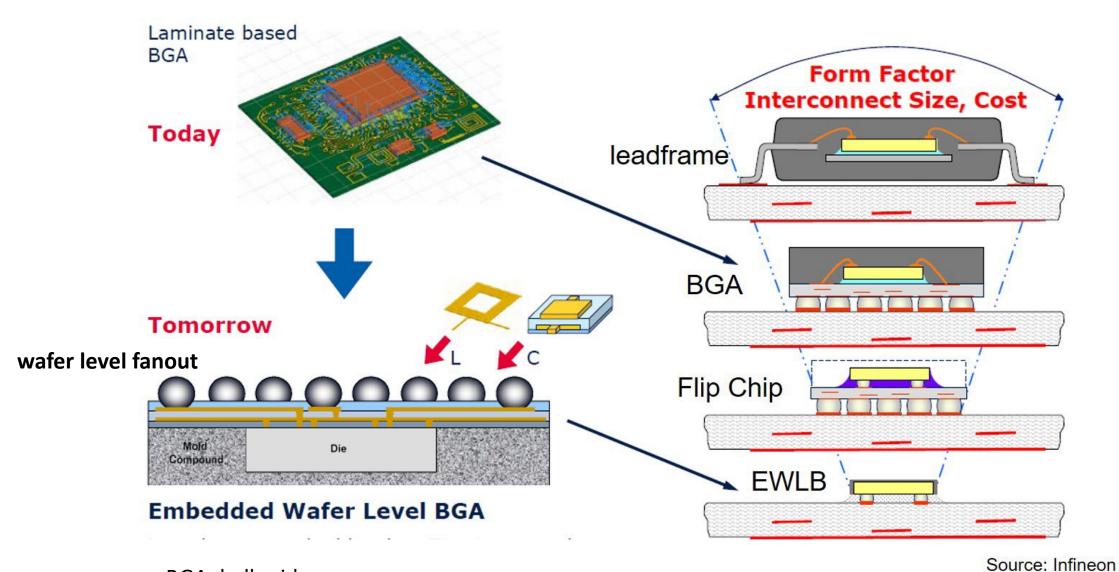
# molding







https://elimold.com/industries/semiconductor-injection-molding/

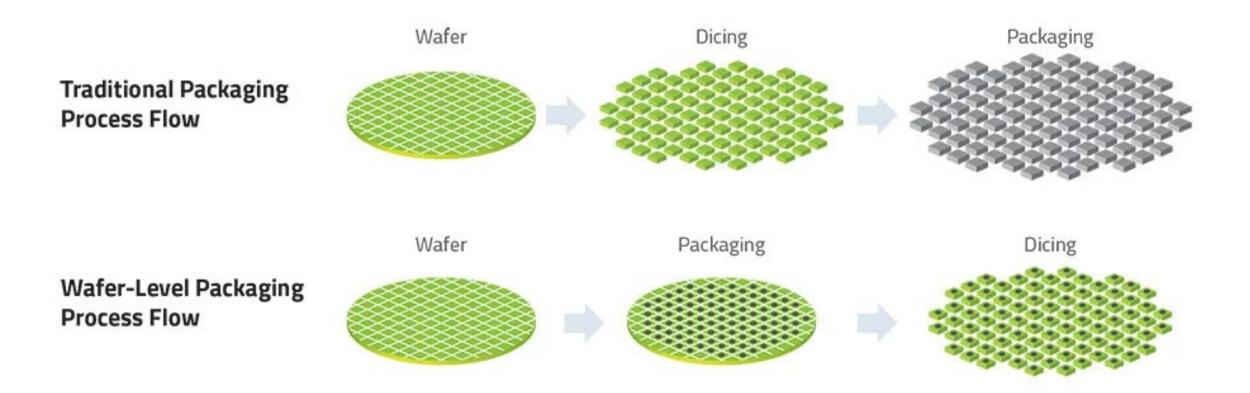


BGA: ball grid array

EWLB: embedded wafer level BGA

PBGA: plastic ball grid array

https://polymerinnovationblog.com/polymers-electronic-packaging-part-one-introduction-mold-compounds/



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